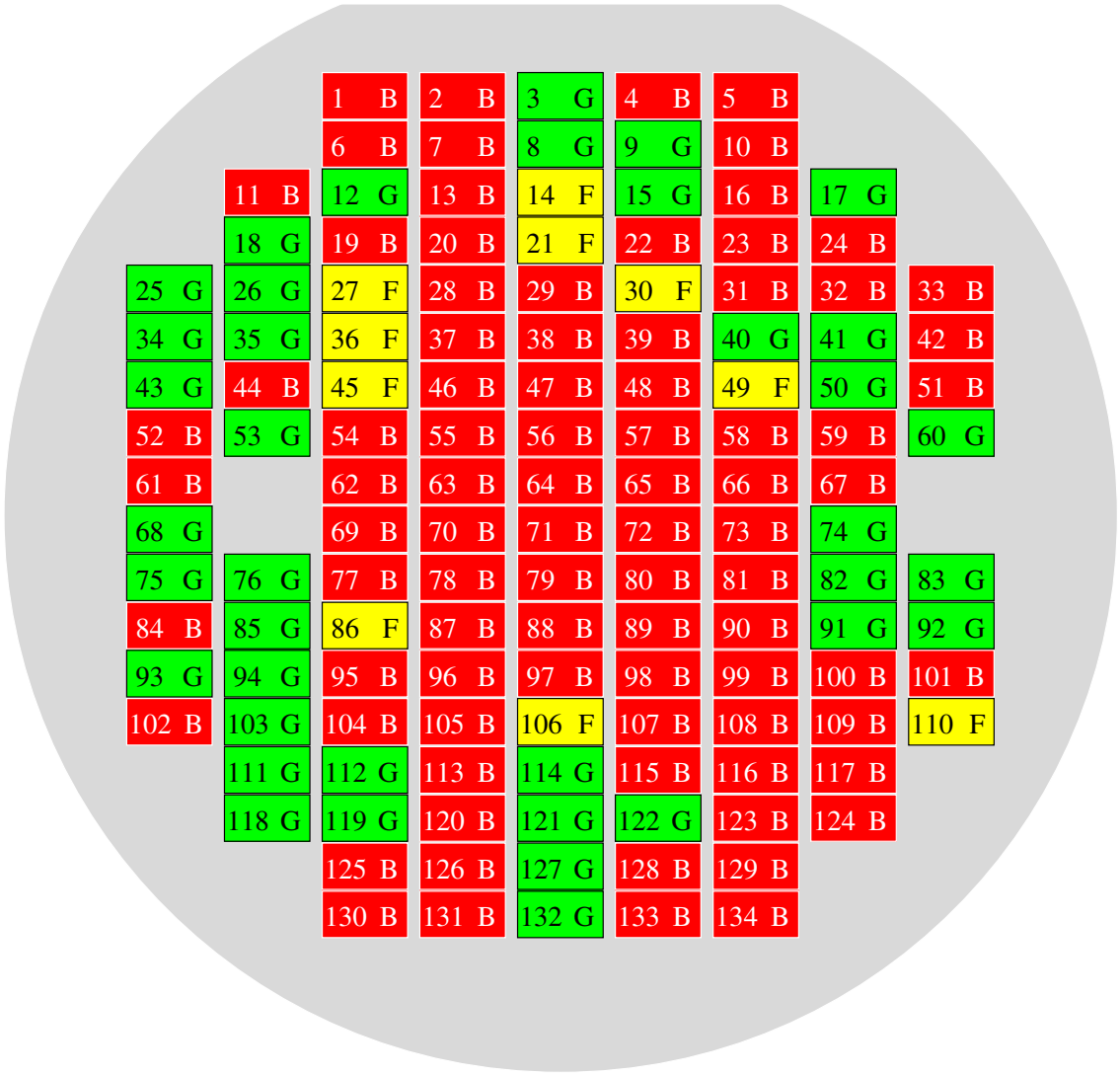
Die quality map for wafer 170 s/n: Y21316-12-18

Date: 07/06/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged